

Application/Control No.	Applicant(s)/Patent und Reexamination	der
09/494,514	NAVEEN ET AL.	
Examiner	Art Unit	
Michael W. Bowen	2625	

	SEARCHED				
Class	Subclass	Date	Examiner		
382	305 partial search	7/5/05			
707	1-7, 104.1 partial	7/06/05	MWB		
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INT	INTERFERENCE SEARCHED				
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Class & text search US PAT, US PG-PUB 345/418-475, 581-689 348/445, 556, 571-721, 844, 913 382/108, 155-231, 254-308, 325 706/934 707/1-7, 104.1	6/26/05	MWB		
Search backward citation of US PAT 6,082,746 Naveen Note related application 09/495642	7/5/05	MWB.		
Text search: IEEE Xplore ACM	7/6/05	MWB		
Text search on EAST: EPO, JPO, DERWENT	7/6/05	MWB		
updated:	319/06	Js		